

Notice of References Cited

Application/Control No.

10/796,599

Applicant(s)/Patent Under
Reexamination
FENG, WEISHI

Examiner

MARTIN JERIKO P. SAN JUAN

Art Unit

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0195891 A1	10-2003	Marsh, David J.	707/100
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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